



APPROVAL SHEET

Approval Specification	Customer's Approval Certificate
<p>TO:</p> <p>Part No.:</p> <p>Customer's Part No.:</p>	<p>Please return this copy as a certification of your approval</p> <p>Checked & Approved by:</p> <p>Date:</p>

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Part No.	:	SF1188
Pages	:	6
Date	:	2013/6/14
Revision	:	1.0

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Application

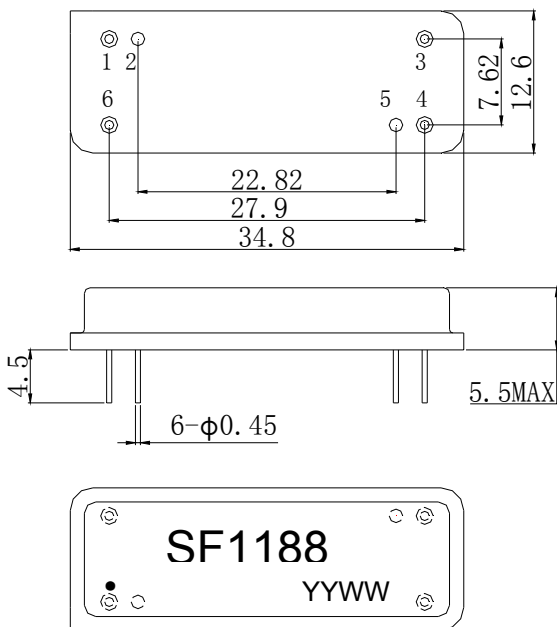
- Low amplitude ripple
- Sharp rejections at both out-bands
- Usable passband 24 MHz

Features

- RoHS compatible
- Package size 34.8x12.6x5.50mm³
- Package Code DIP3512J
- Electrostatic Sensitive Device(ESD)



Package Dimensions (Unit: mm)



Pin Configuration

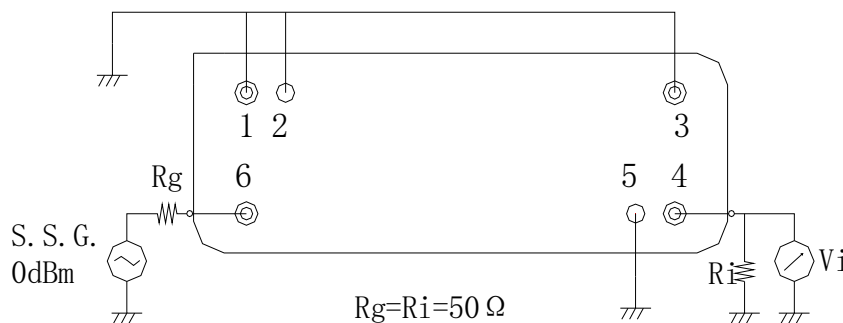
Pin No.	Description
6	Input
4	Output
1,2,3,5	Ground

Marking Description

S	Trademark
F	SAW Filter
1188	Part Number
●	Pin 1
YYWW	Year Code & Week Code

*Fig: If the products produced in 06th week of 2012, The year code & week code is 1206.

Test Circuit



Performance**Maximum Rating**

Item		Value	Unit
DC Voltage	V_{DC}	3	V
Operation Temperature	T	-40 ~ +85	°C
Storage Temperature	T_{stg}	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

Electronic Characteristics

Test Temperature: $25^{\circ}\text{C} \pm 2^{\circ}\text{C}$

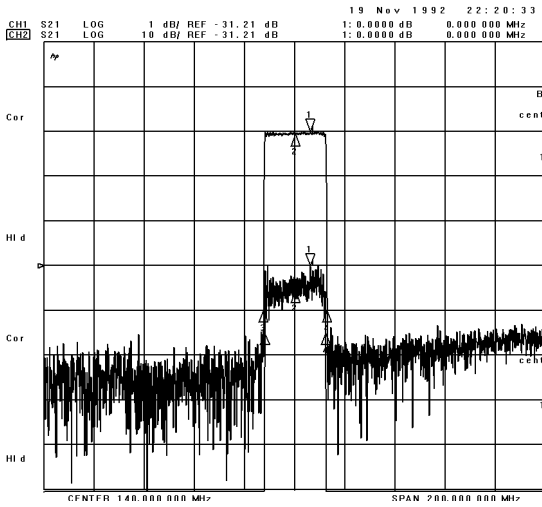
Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

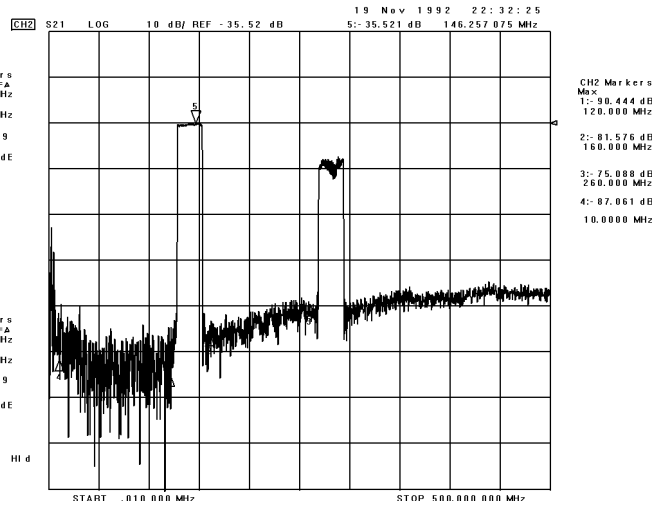
Item		Minimum	Typical	Maximum	Unit
Center Frequency	f_c	139.8	140.0	140.2	MHz
Insertion Loss(min)	IL		31.3	31.5	dB
Amplitude Ripple (p-p) 128.50-151.50MHz	Δa		1.3	1.5	dB
3 dB Bandwidth	BW_{3dB}	24.6	24.8		MHz
40 dB Bandwidth	BW_{40dB}		25.6	26.0	MHz
Absolute Attenuation	a				
	50.00-125.00 MHz	40.0	45.0		dB
	155.00-200.00MHz	40.0	45.0		dB

Frequency Characteristics

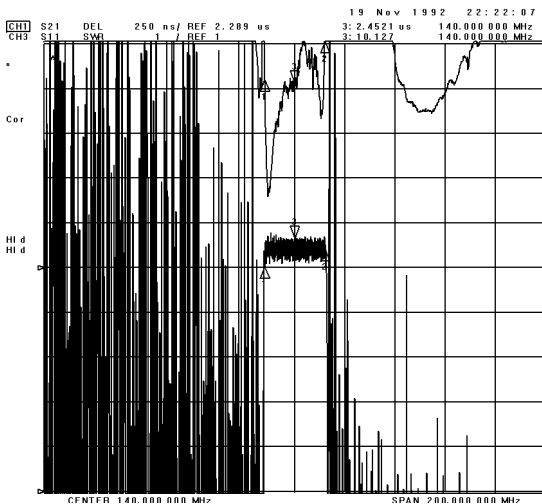
Frequency Response



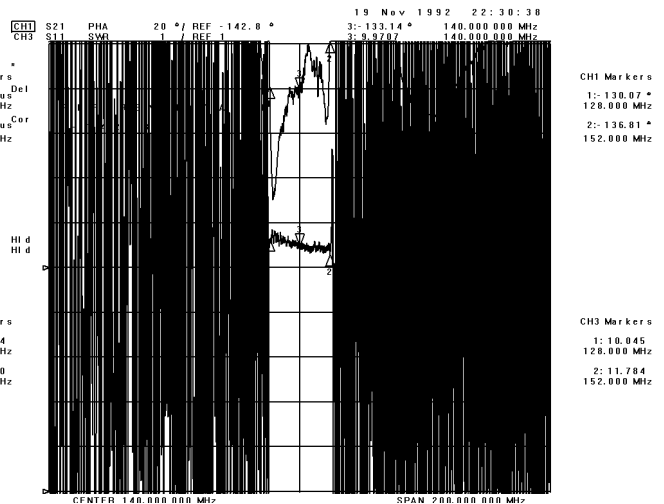
Frequency Response (wideband)



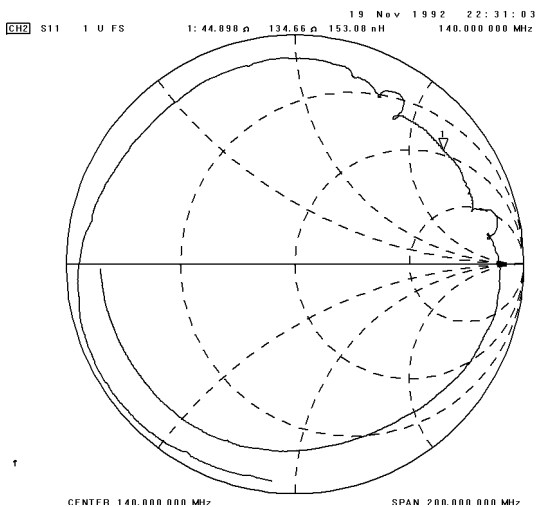
Delay Ripple & S11 VSWR



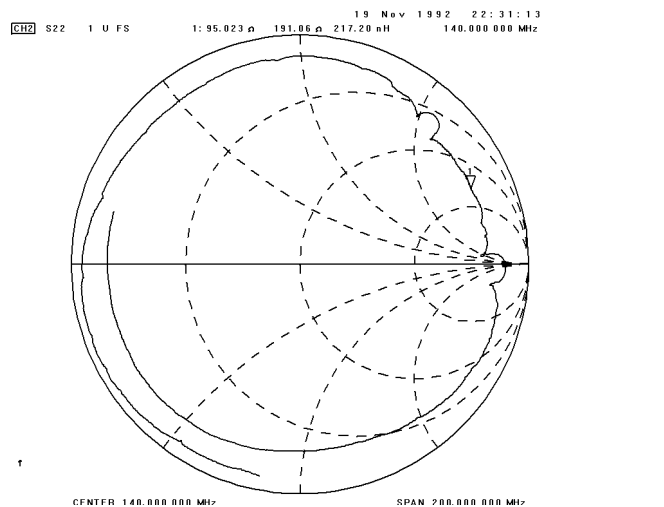
Phase Linearity & S22 VSWR



S11 Smith Chart

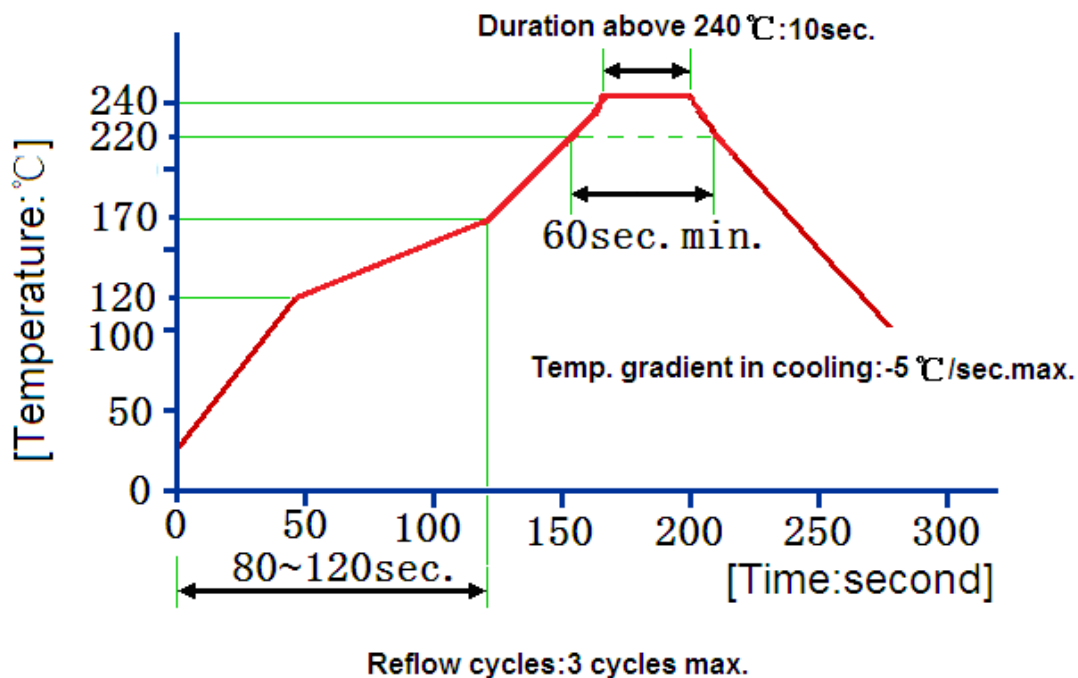


S22 Smith Chart



Reliability (The SAW components shall remain electrical performance after tests)

No.	Test item	Test condition
1	Temperature Storage	(1) Temperature: $85^{\circ}\text{C} \pm 2^{\circ}\text{C}$, Duration: 250h, Recovery time: $2\text{h} \pm 0.5\text{h}$ (2) Temperature: $-55^{\circ}\text{C} \pm 3^{\circ}\text{C}$, Duration: 250h, Recovery time: $2\text{h} \pm 0.5\text{h}$
2	Humidity Test	Conditions: $60^{\circ}\text{C} \pm 2^{\circ}\text{C}$, 90~95% RH Duration: 250h
3	Thermal Shock	Heat cycle conditions: $T_A = -55^{\circ}\text{C} \pm 3^{\circ}\text{C}$, $T_B = 85^{\circ}\text{C} \pm 2^{\circ}\text{C}$, $t_1 = t_2 = 30\text{min}$, Switch time: $\leq 3\text{min}$, Cycle time: 100 times, Recovery time: $2\text{h} \pm 0.5\text{h}$.
4	Vibration Fatigue	Frequency of vibration: 10~55Hz Amplitude: 1.5mm Directions: X,Y and Z Duration: 2h
5	Drop Test	Cycle time: 10 times Height: 1.0m
6	Solder Ability Test	Temperature: $245^{\circ}\text{C} \pm 5^{\circ}\text{C}$ Duration: 3.0s--5.0s Depth: DIP--2/3, SMD--1/5
7	Resistance to Soldering Heat	(1) Thickness of PCB: 1mm, Solder condition: $260^{\circ}\text{C} \pm 5^{\circ}\text{C}$, Duration: $10 \pm 1\text{s}$ (2) Temperature of Soldering Iron: $350^{\circ}\text{C} \pm 10^{\circ}\text{C}$, Duration: 3~4s, Recovery time: $2 \pm 0.5\text{h}$

Recommended Reflow Soldering Diagram

Notes

1. As a result of the particularity of inner structure of SAW products, it easy to be breakdown by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.